USPTO JC102 AUG 20 2002 PATENT & TRADEMARK OFFICE

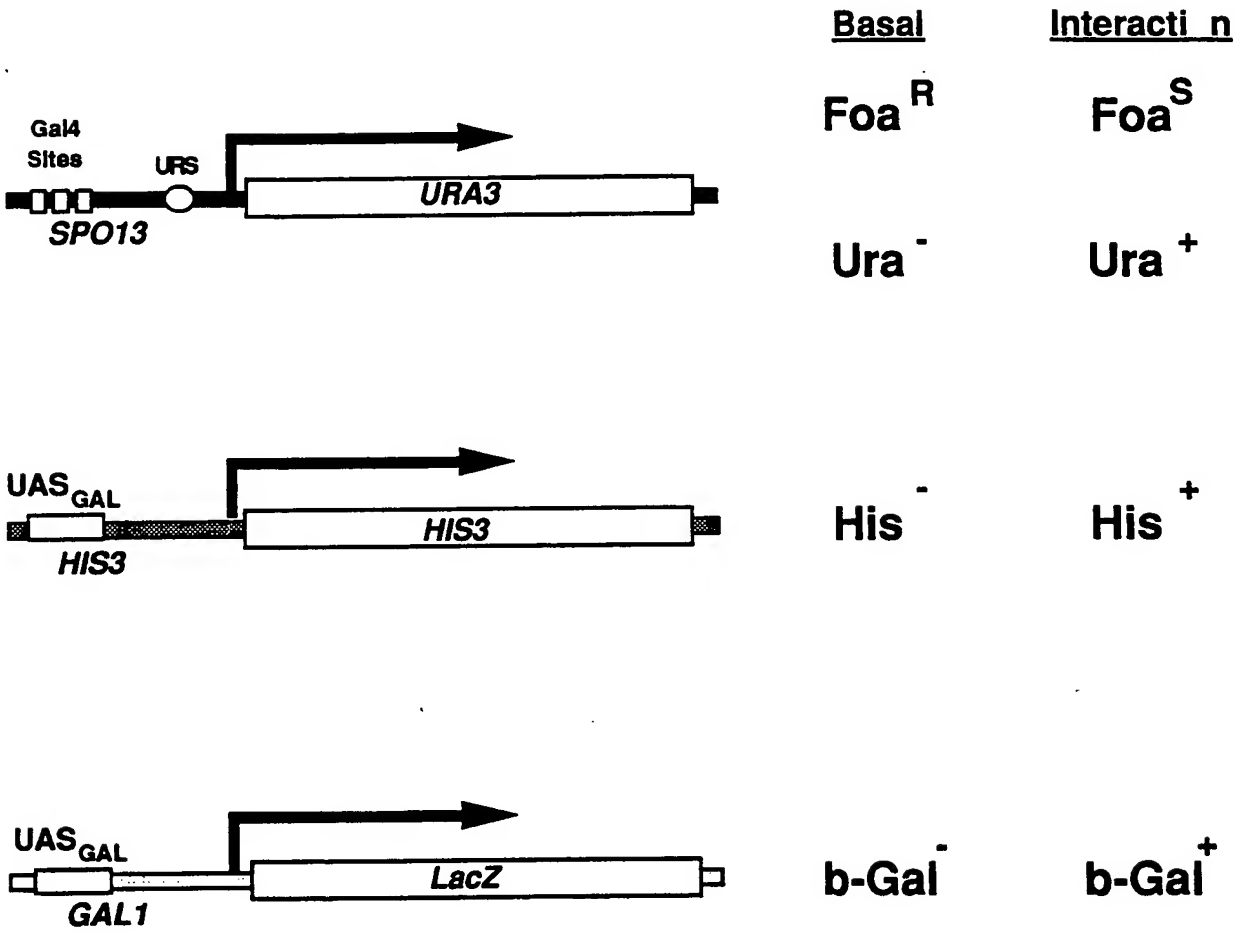

FIG. 1

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JC102

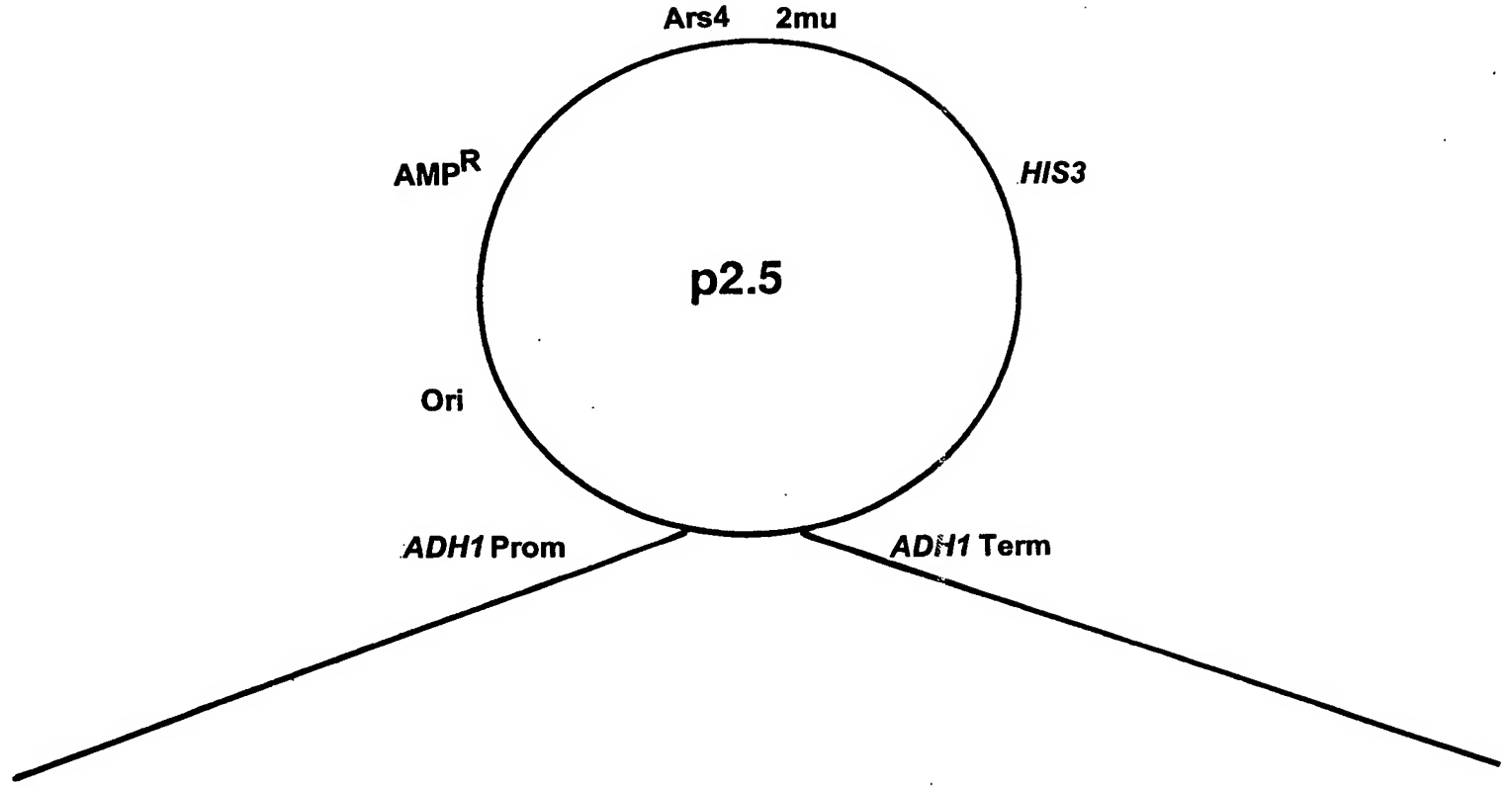

FIG. 2

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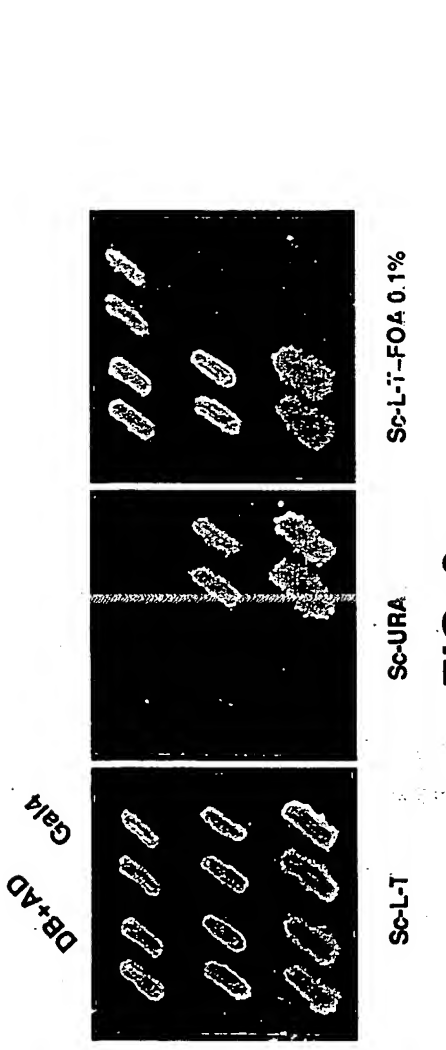

FIG. 3

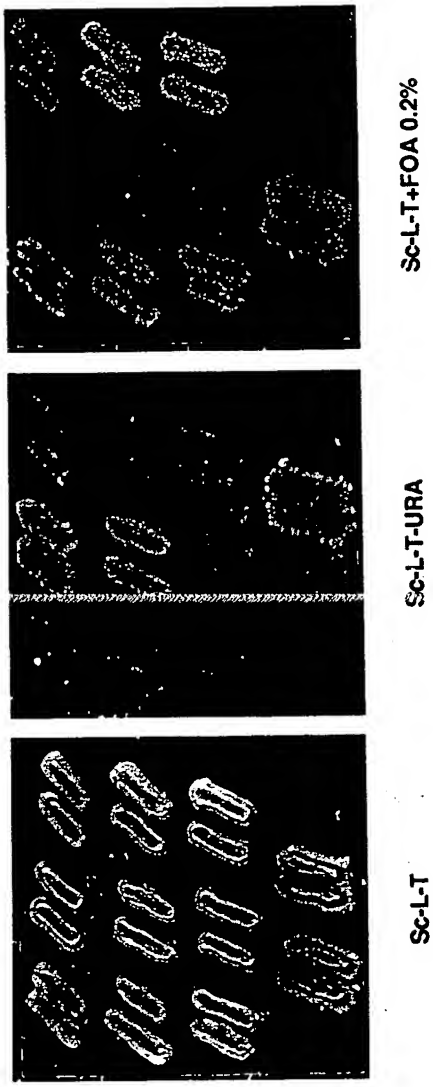

FIG. 5

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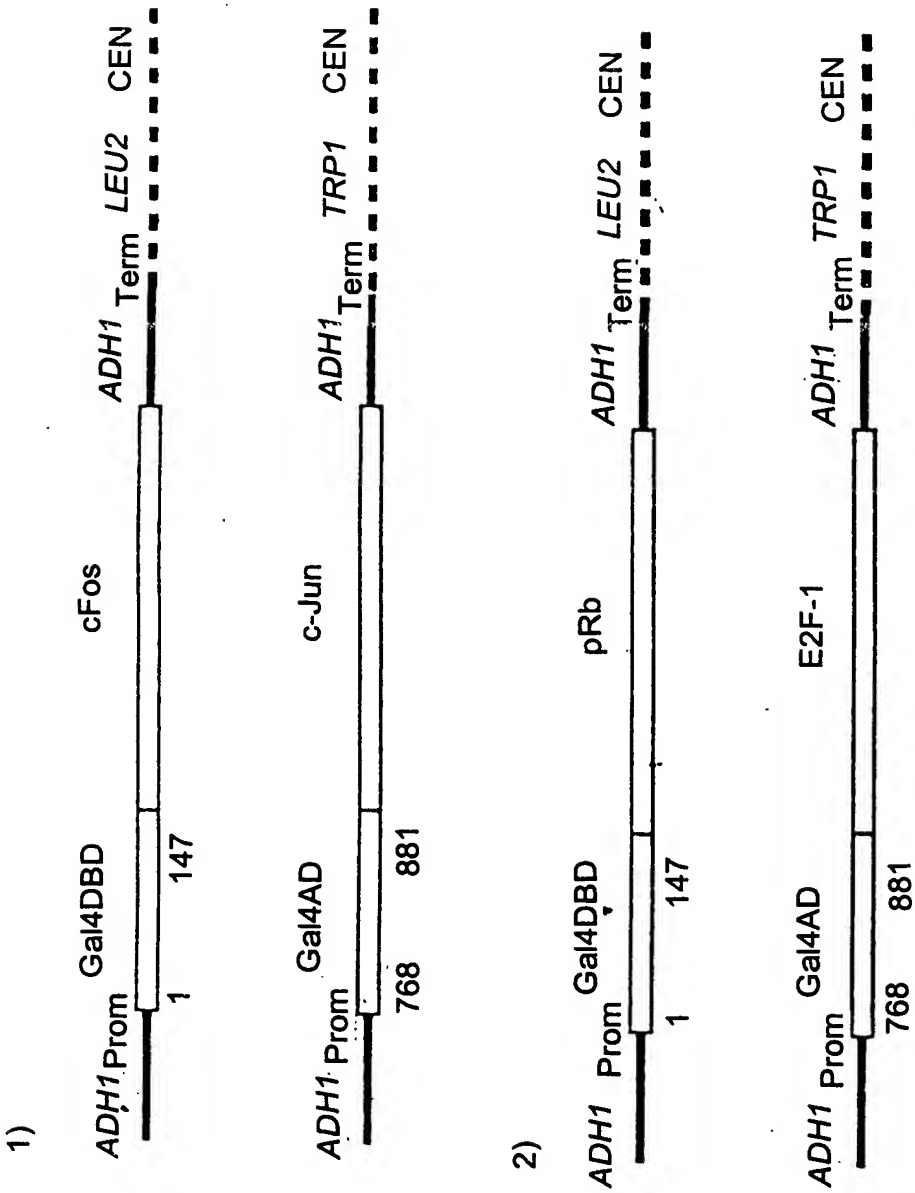

FIG. 4

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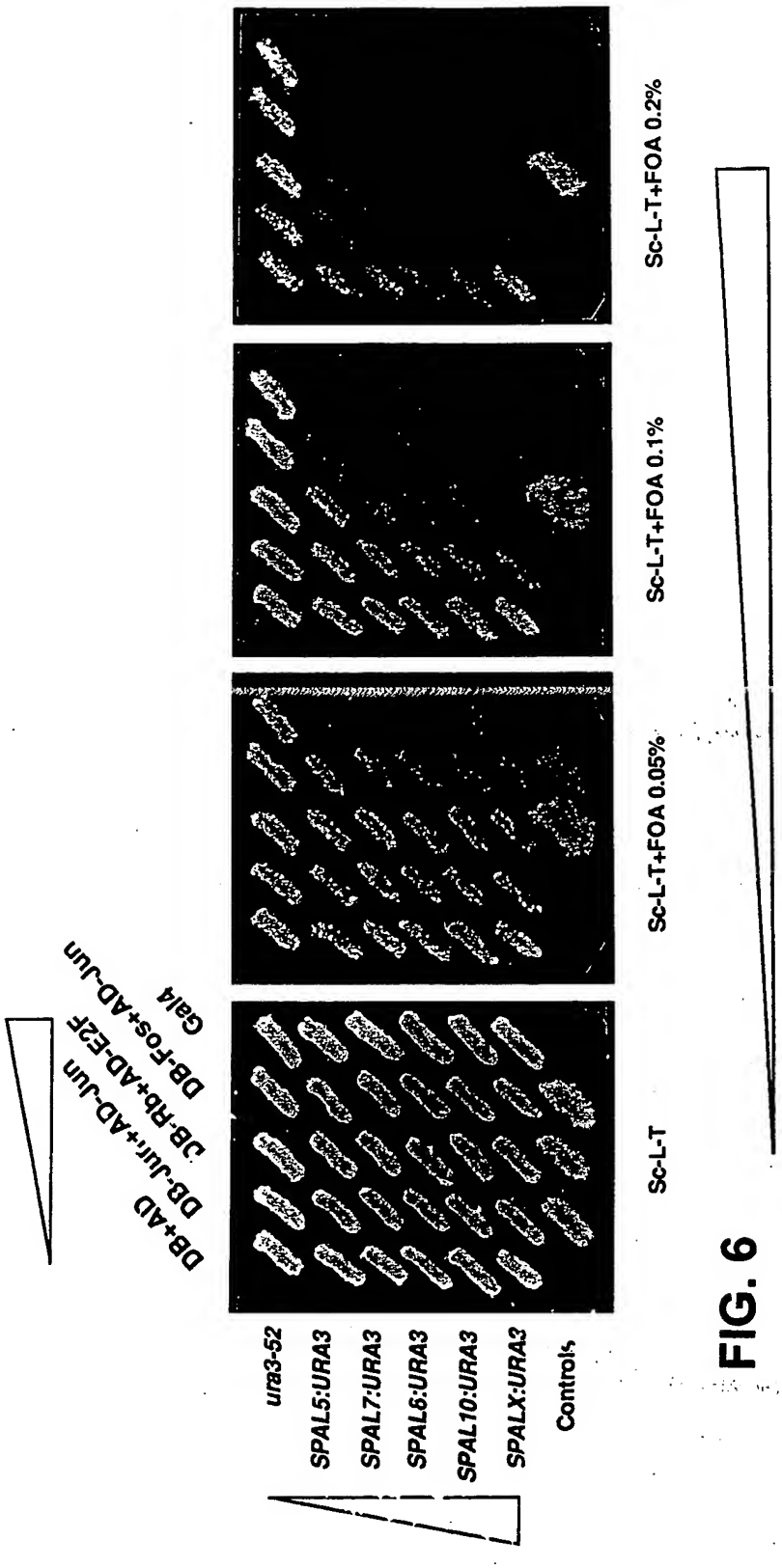

FIG. 6

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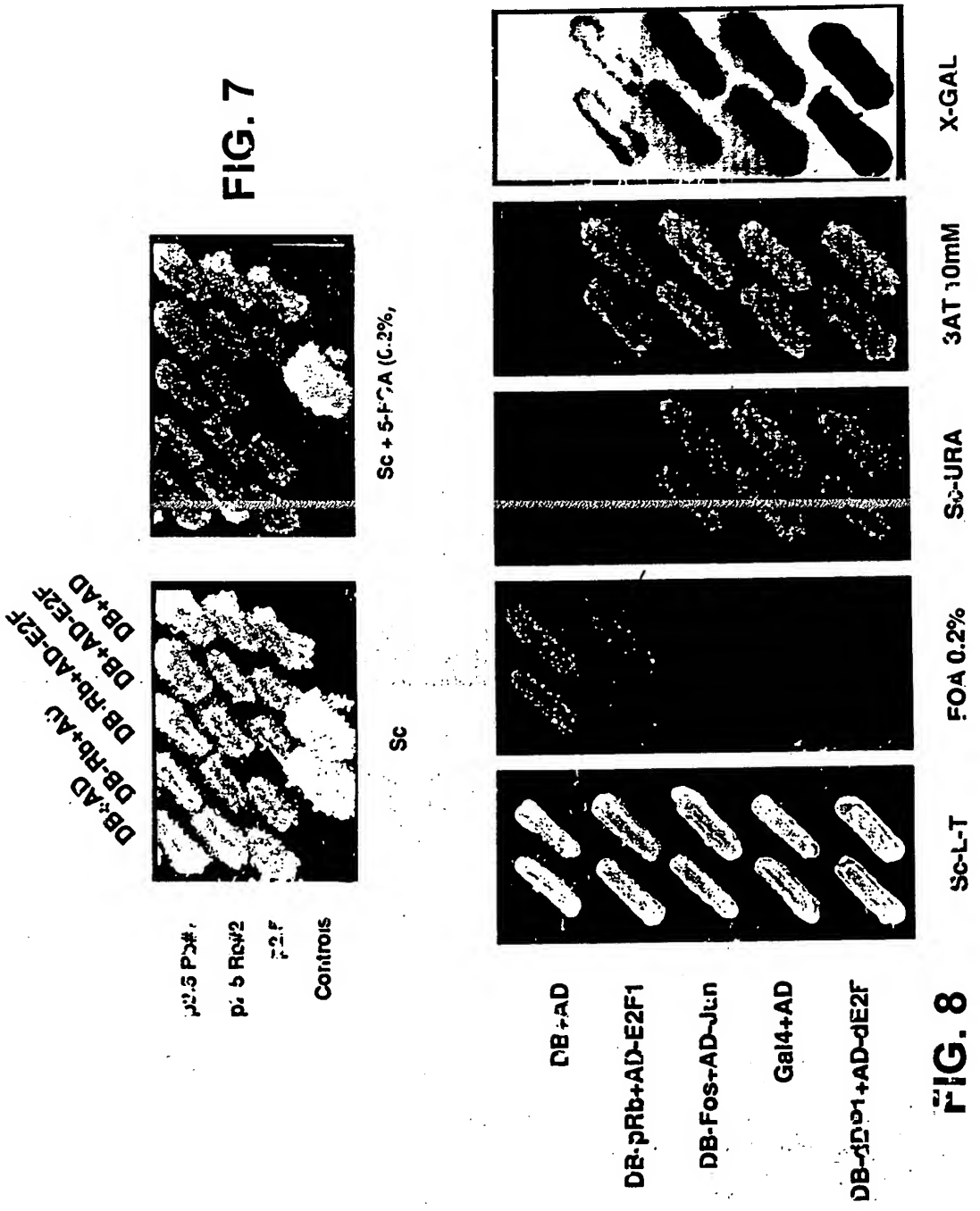

FIG. 7

FIG. 8

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BRID SYSTEMS
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JC1G2

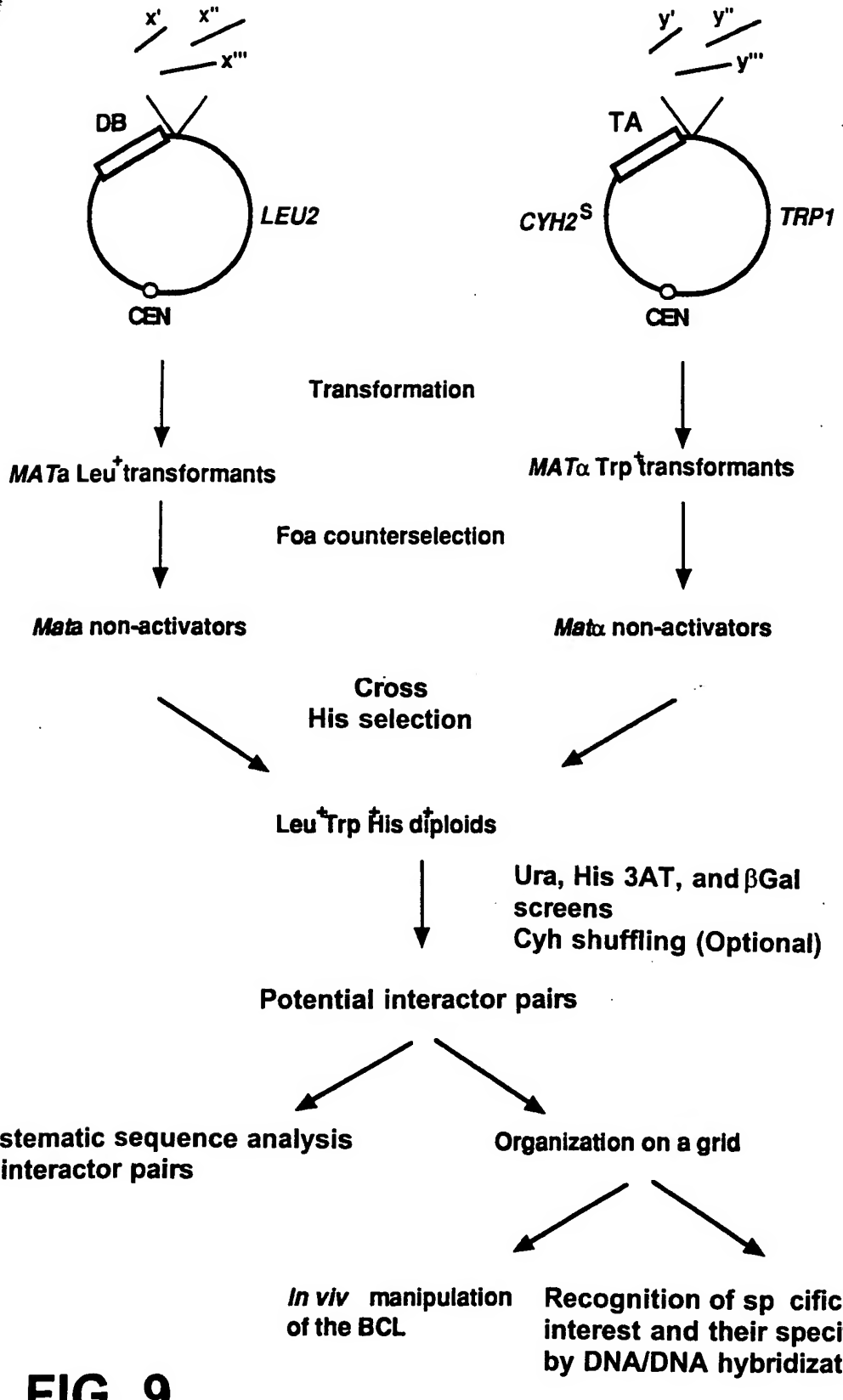

FIG. 9

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OIPE

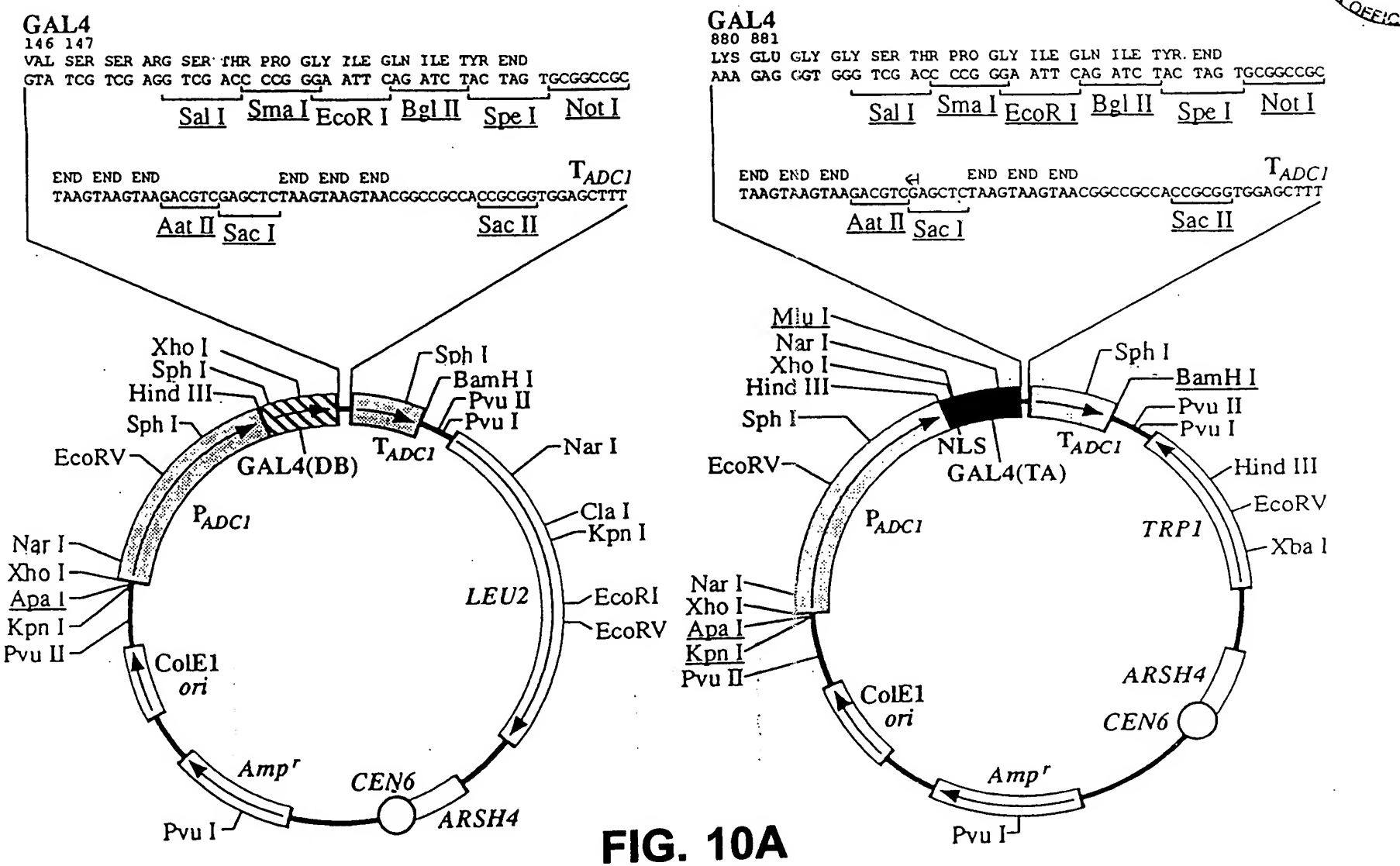

FIG. 10A

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Applicant(s): Marc Vidal et al.
RESPONSE TO CHYBRID SYSTEMS
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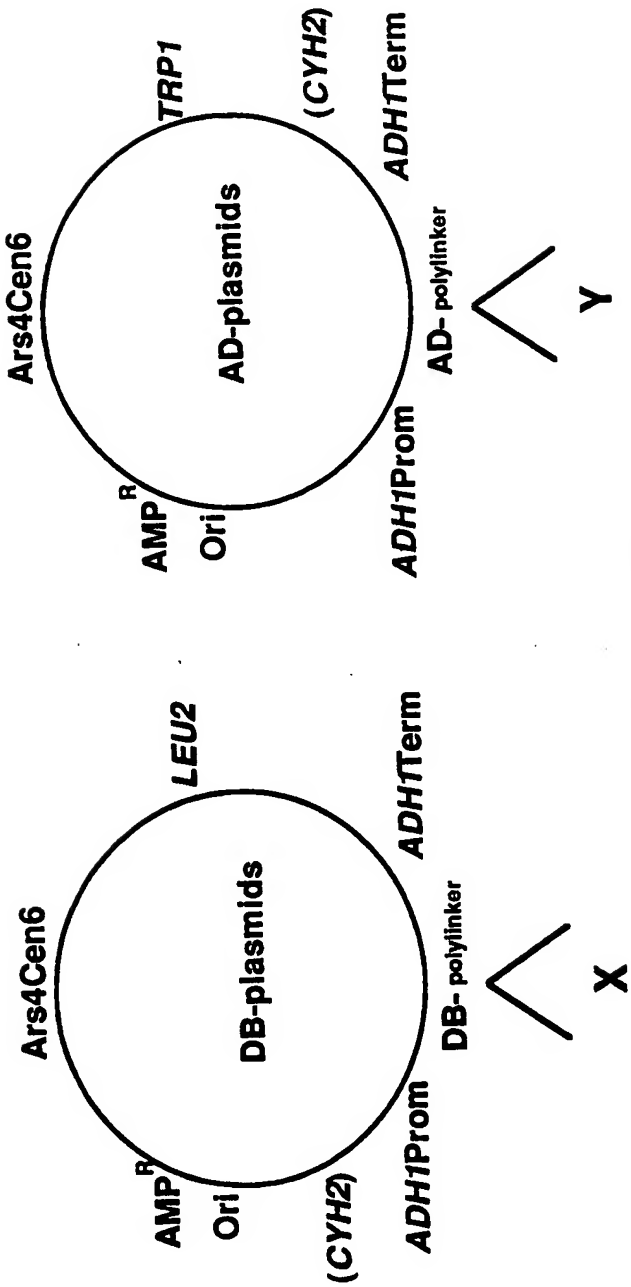

FIG. 10B

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DB-X	Total	His+	Retested	Known interacting	"Novel" interacting	False positive
None	$1x10^6$	1	0			
p130	$5x10^5$	19	9	0	5 → 2	
DP1	$2x10^5$	7	7	6 → 2	1 → 1	
pRb	$1x10^6$	20	0			
p35	$1x10^6$	20	8	0	8 → 2	0
CDK3	$1x10^6$	38	16			
CDK3	$1x10^6$	38	16			
DCC1	$3x10^6$	81	23	0		
Z bu	$1x10^6$	81	23			

FIG. 11

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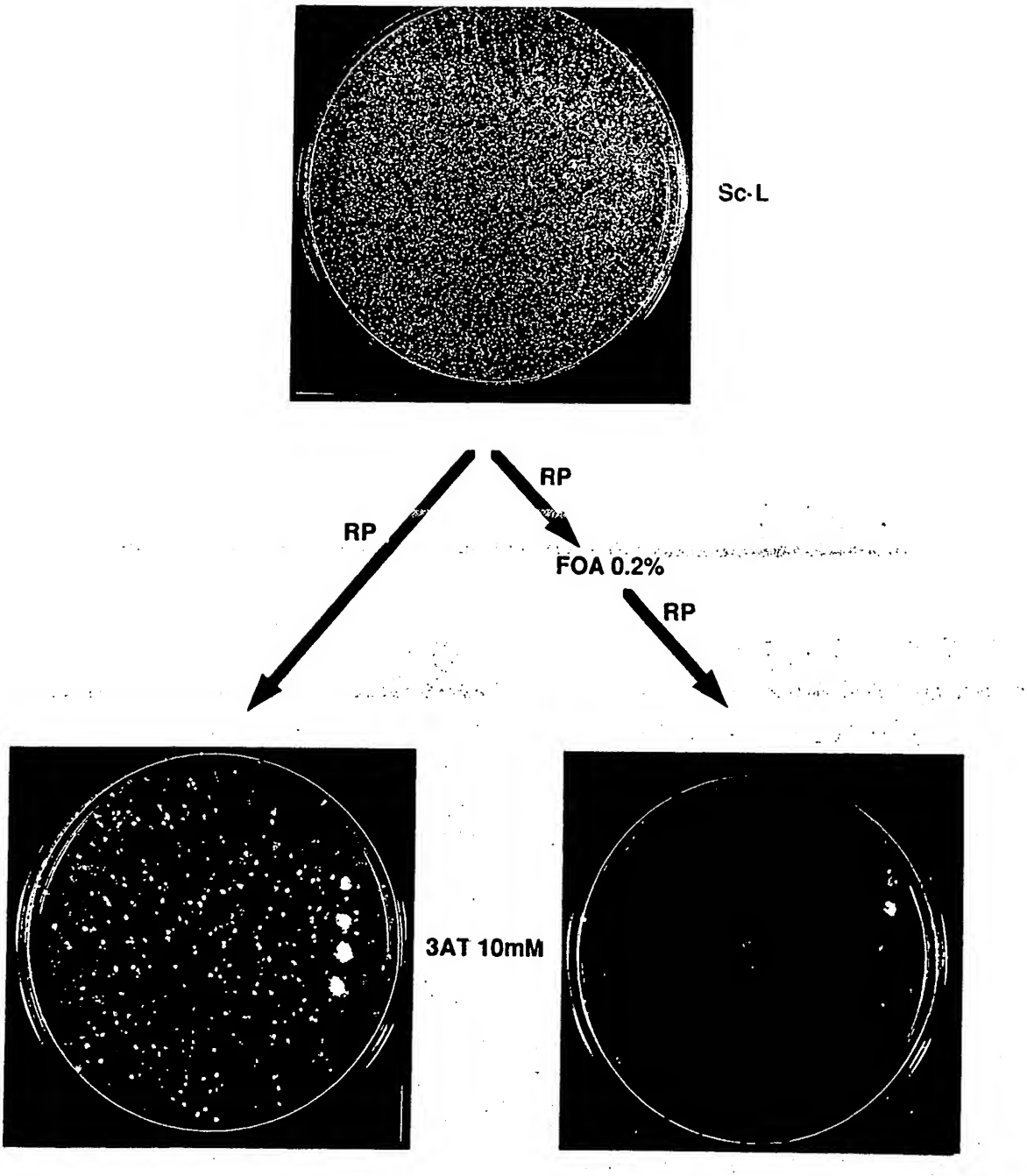

FIG. 12

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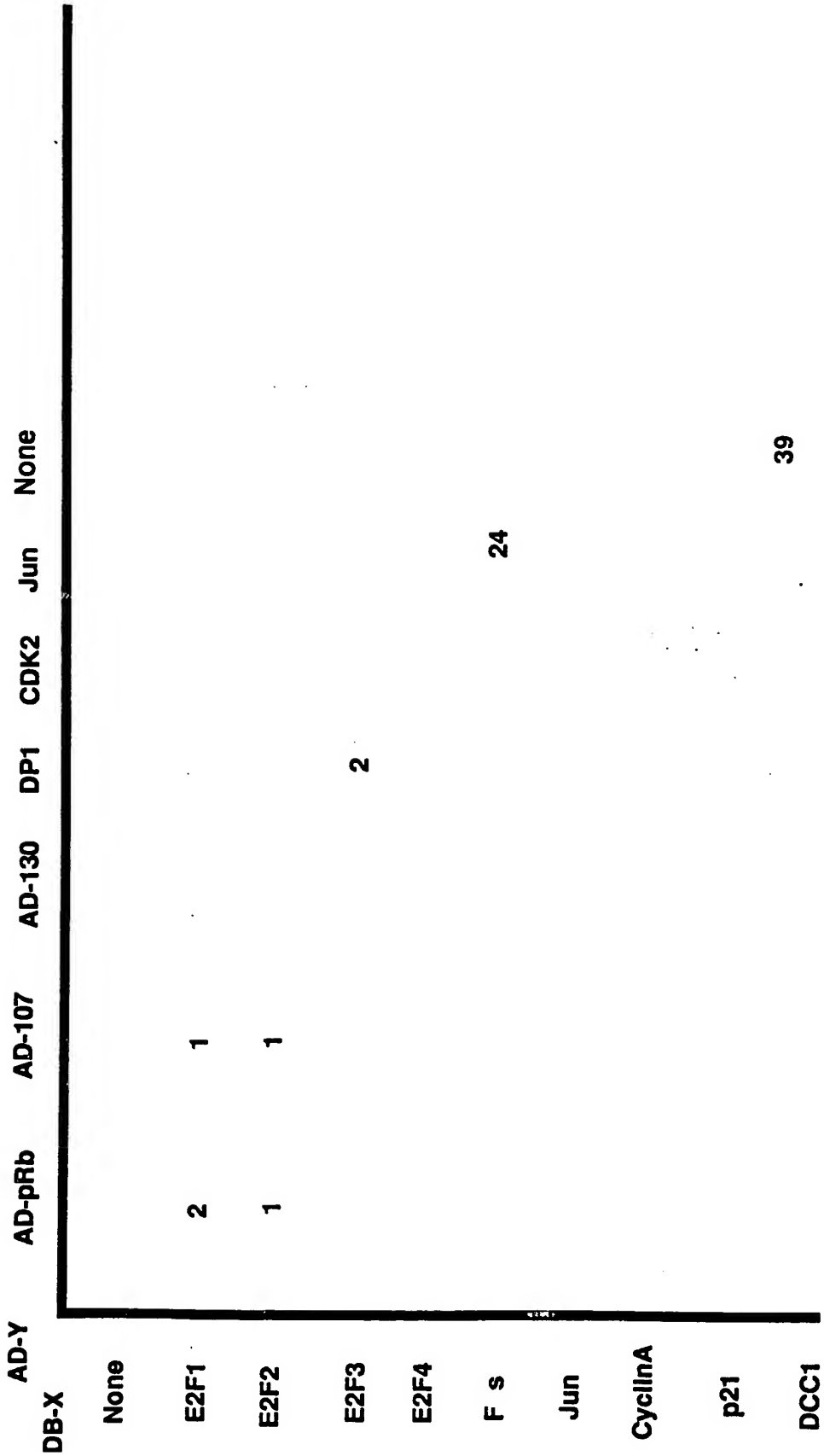

FIG. 13

OIPE
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PATENT & TRADEMARK OFFICE

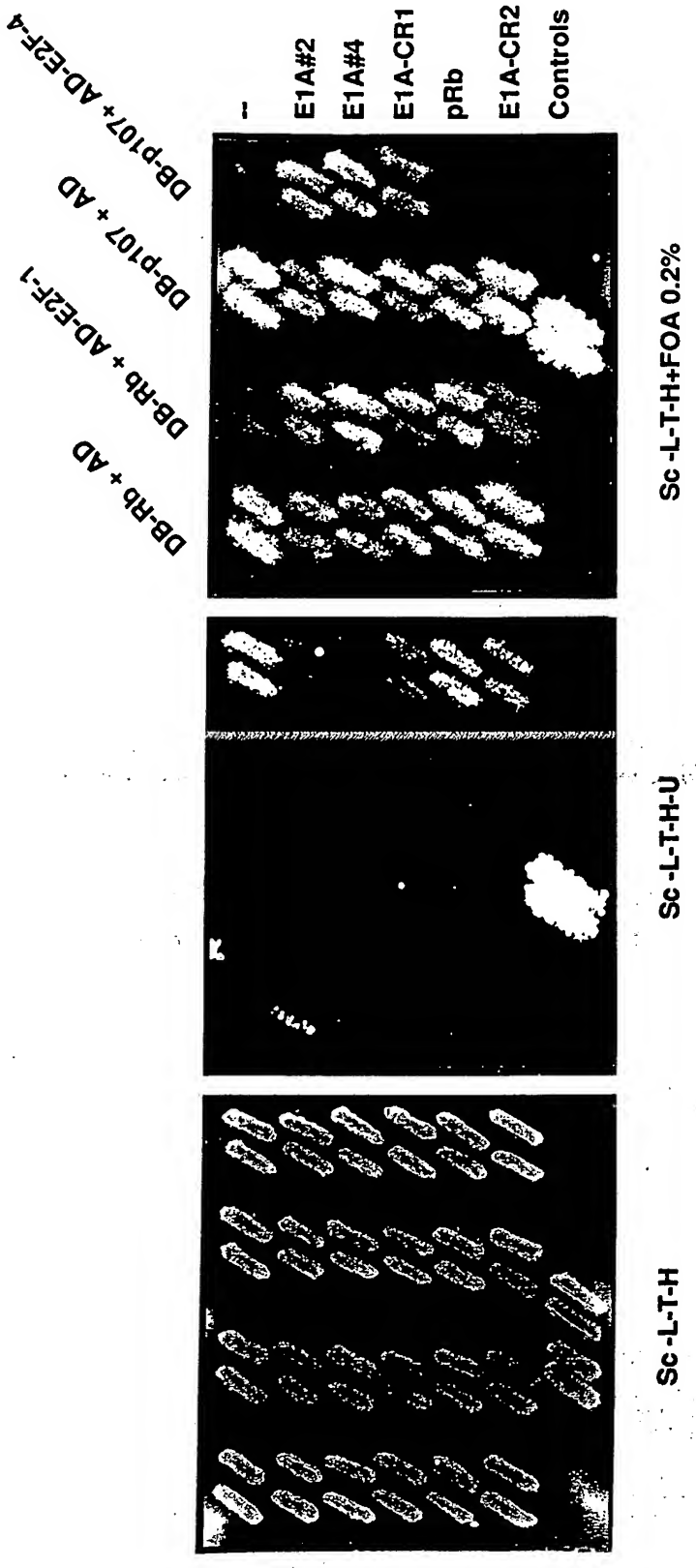

FIG. 14

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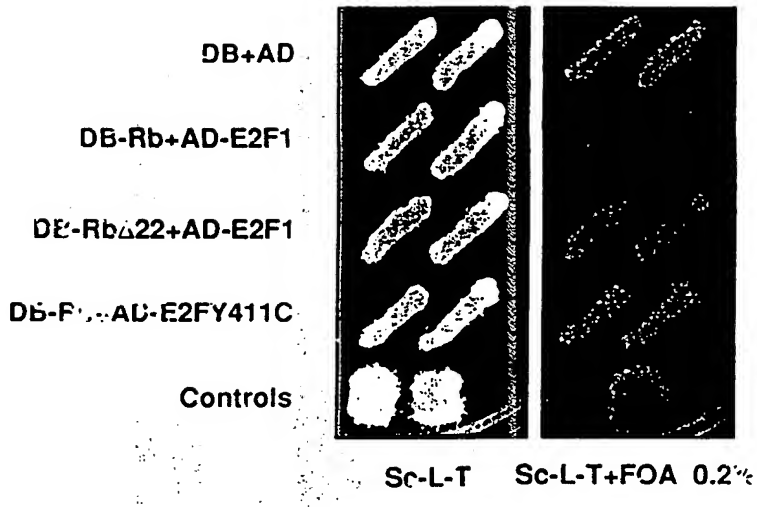

FIG. 15

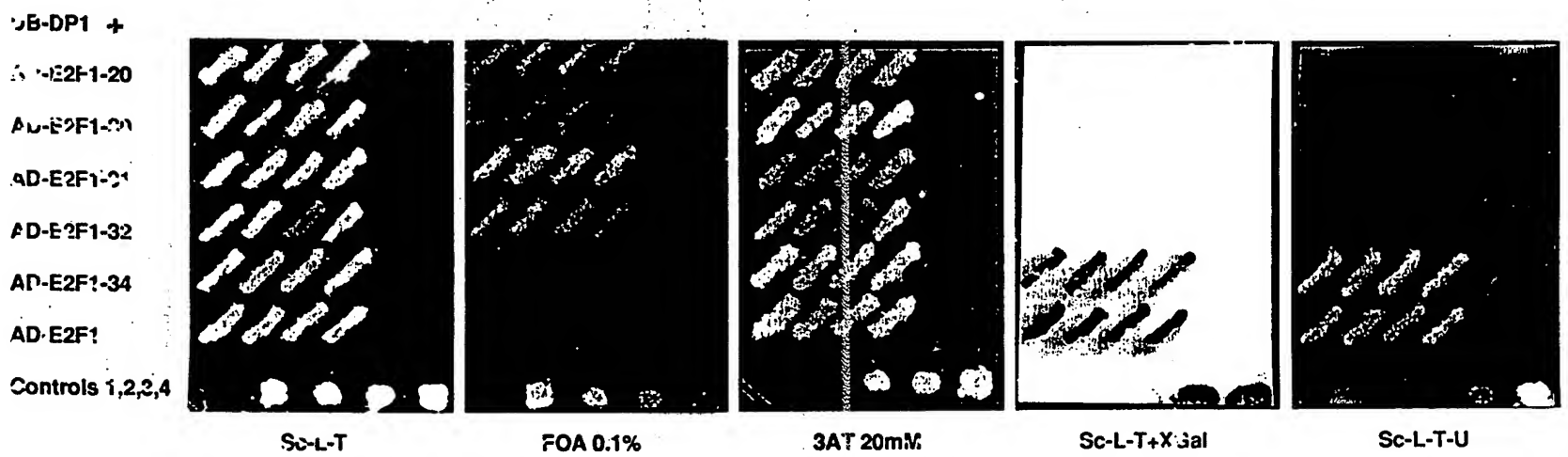

FIG. 20

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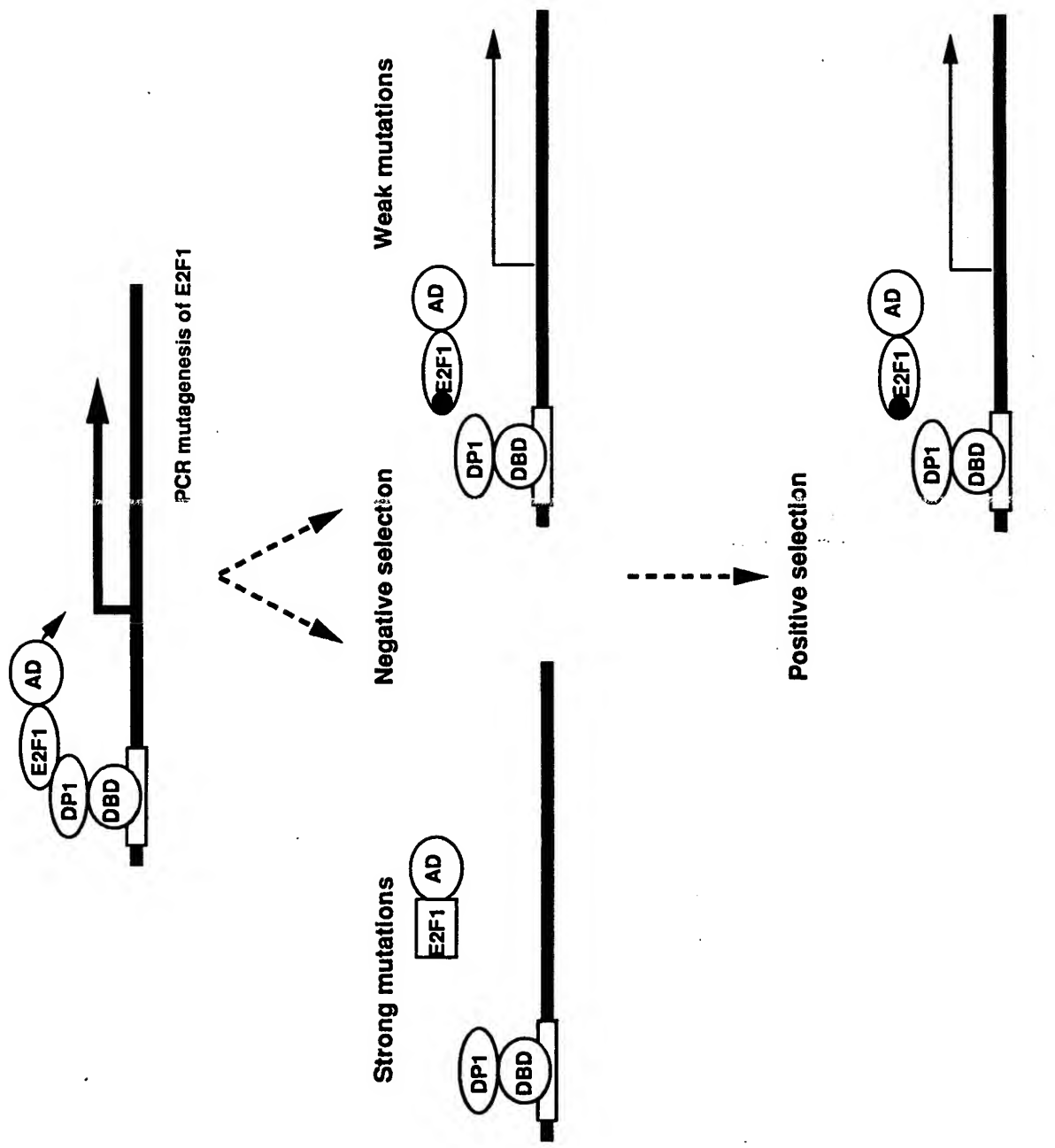

FIG. 16

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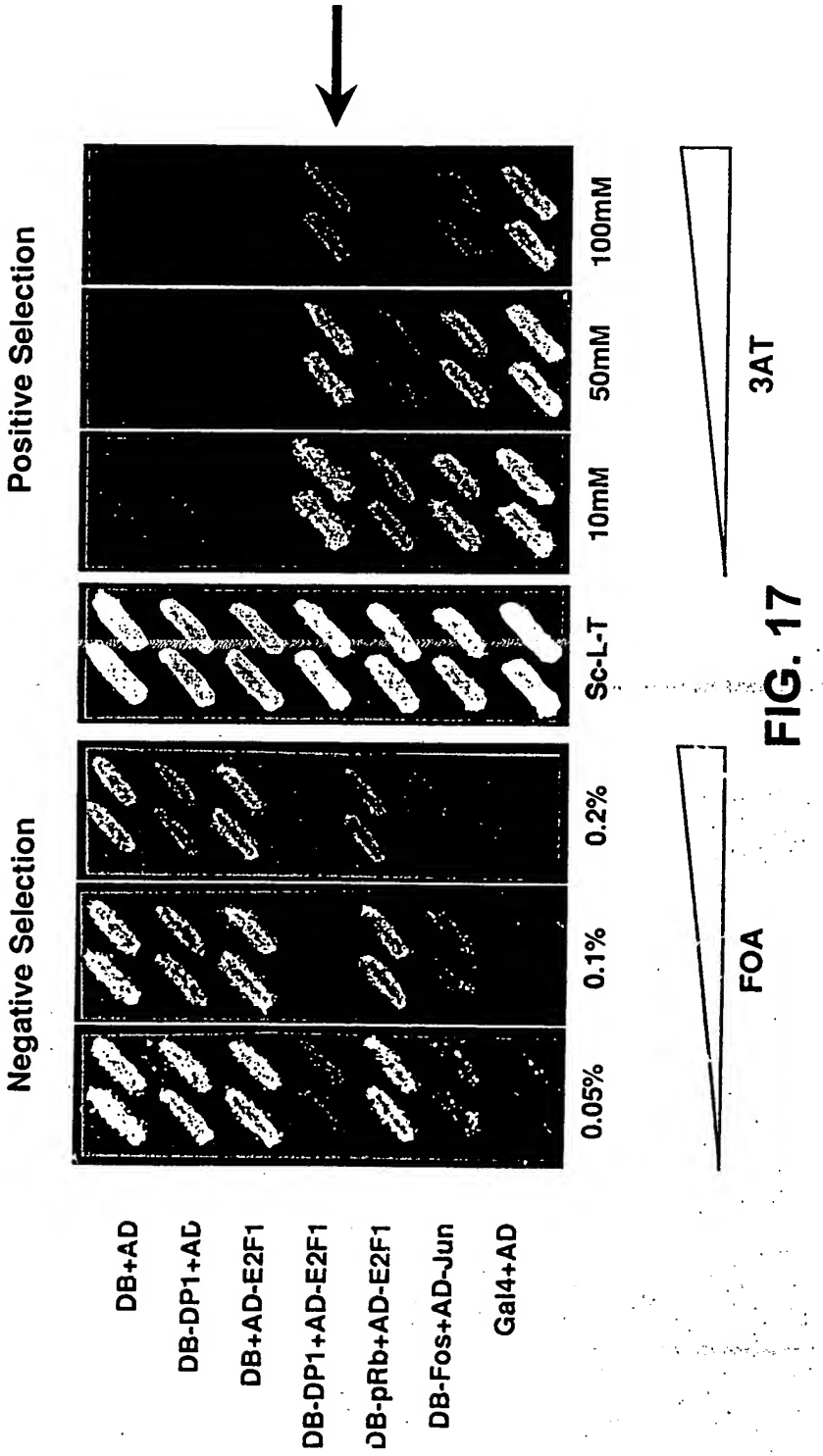

FIG. 17

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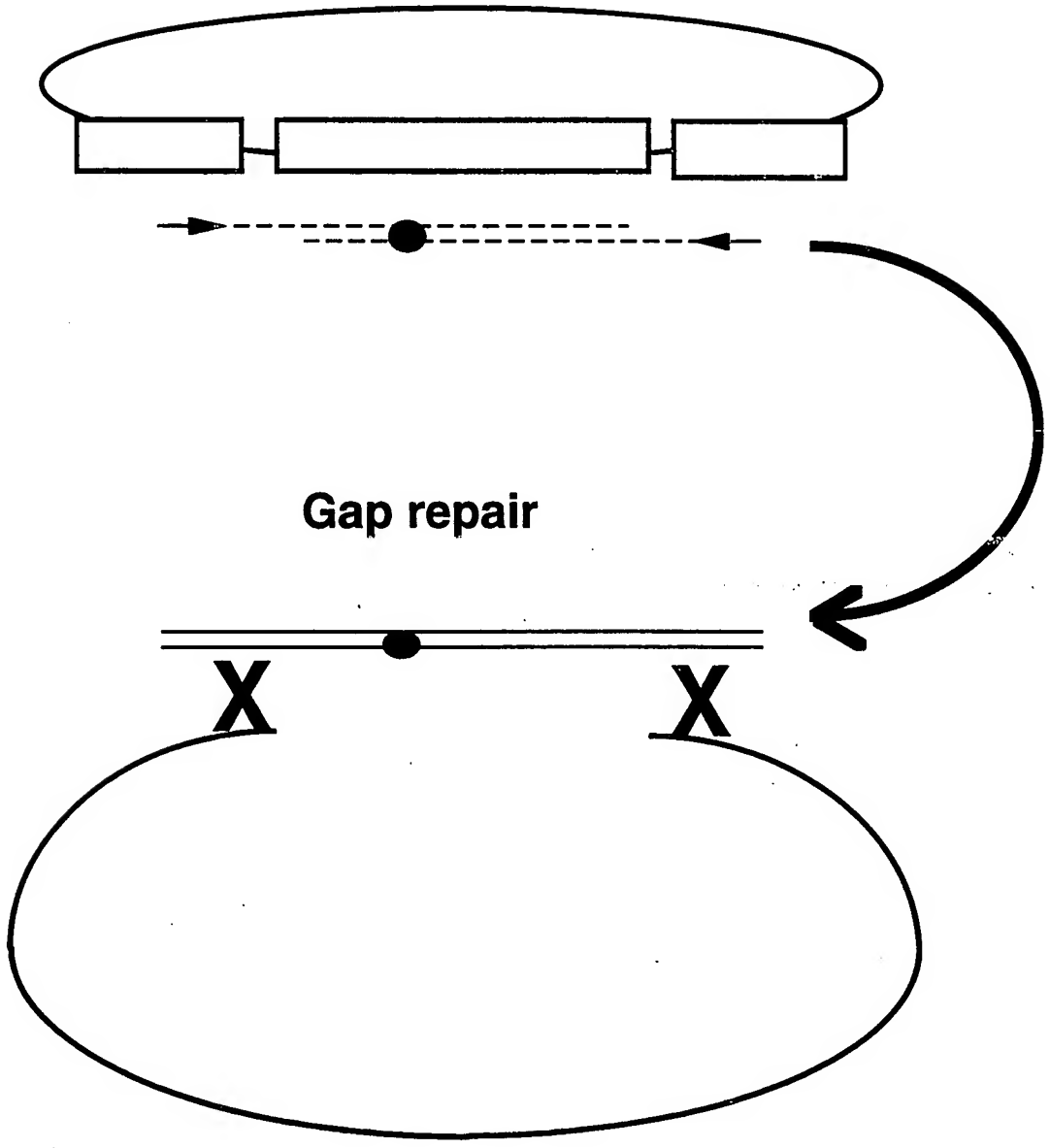

FIG. 18A

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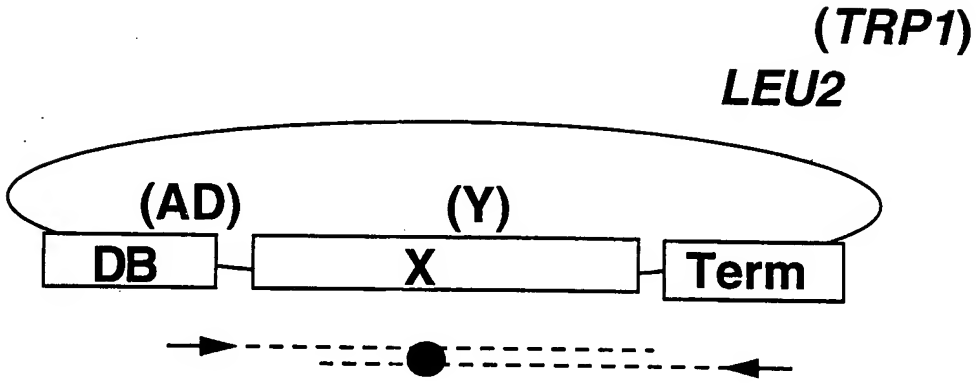
In vitro mutagenic PCR reaction



In vivo gap repair

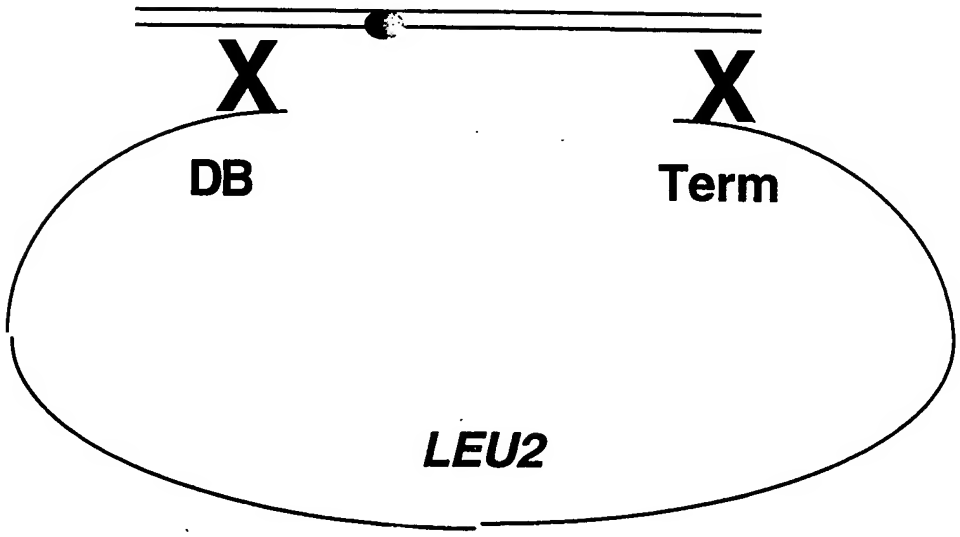


FIG. 18B

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OIPE JC102 AUG 20 2002 PATENT & TRADEMARK OFFICE

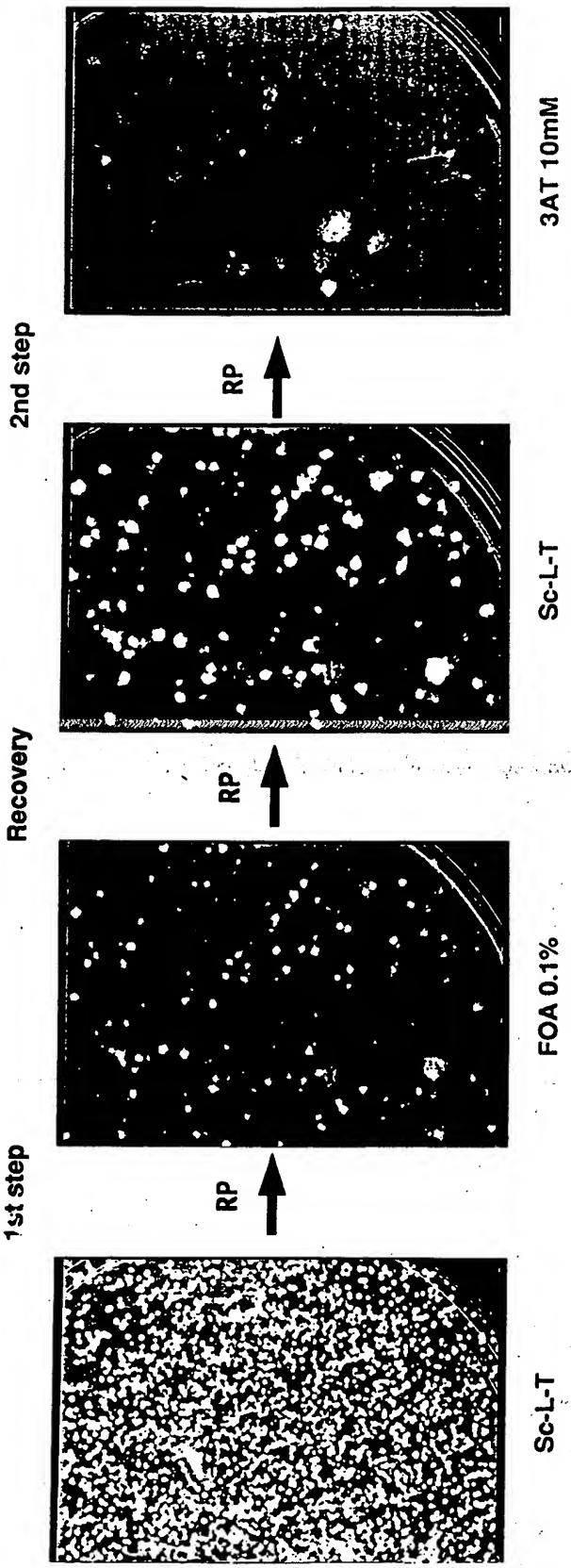

FIG. 19

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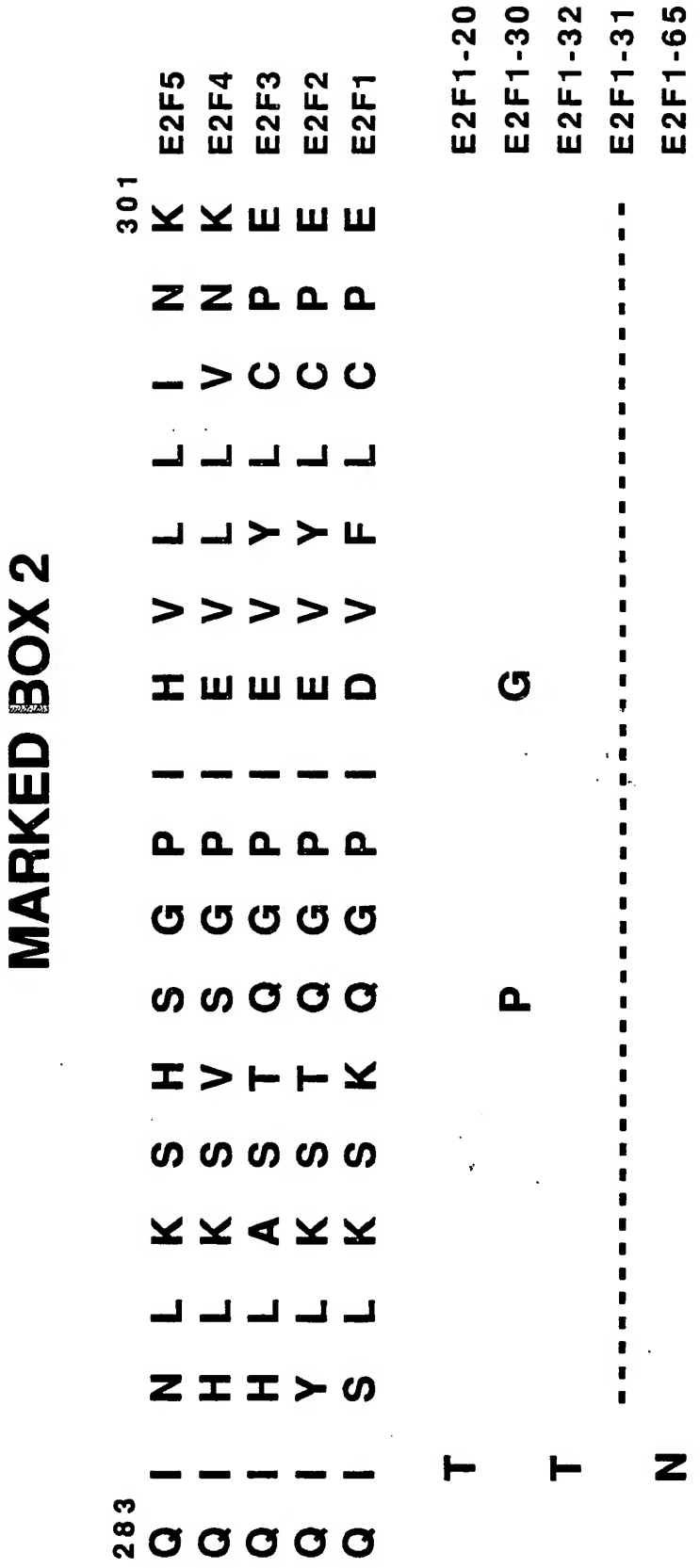

FIG. 21

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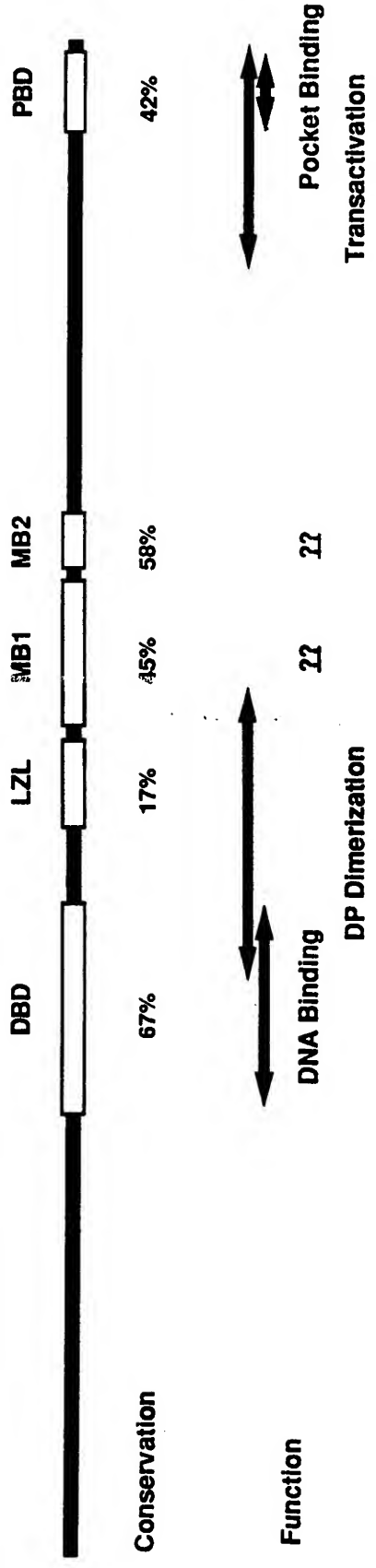

FIG. 22

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AUG 20 2002
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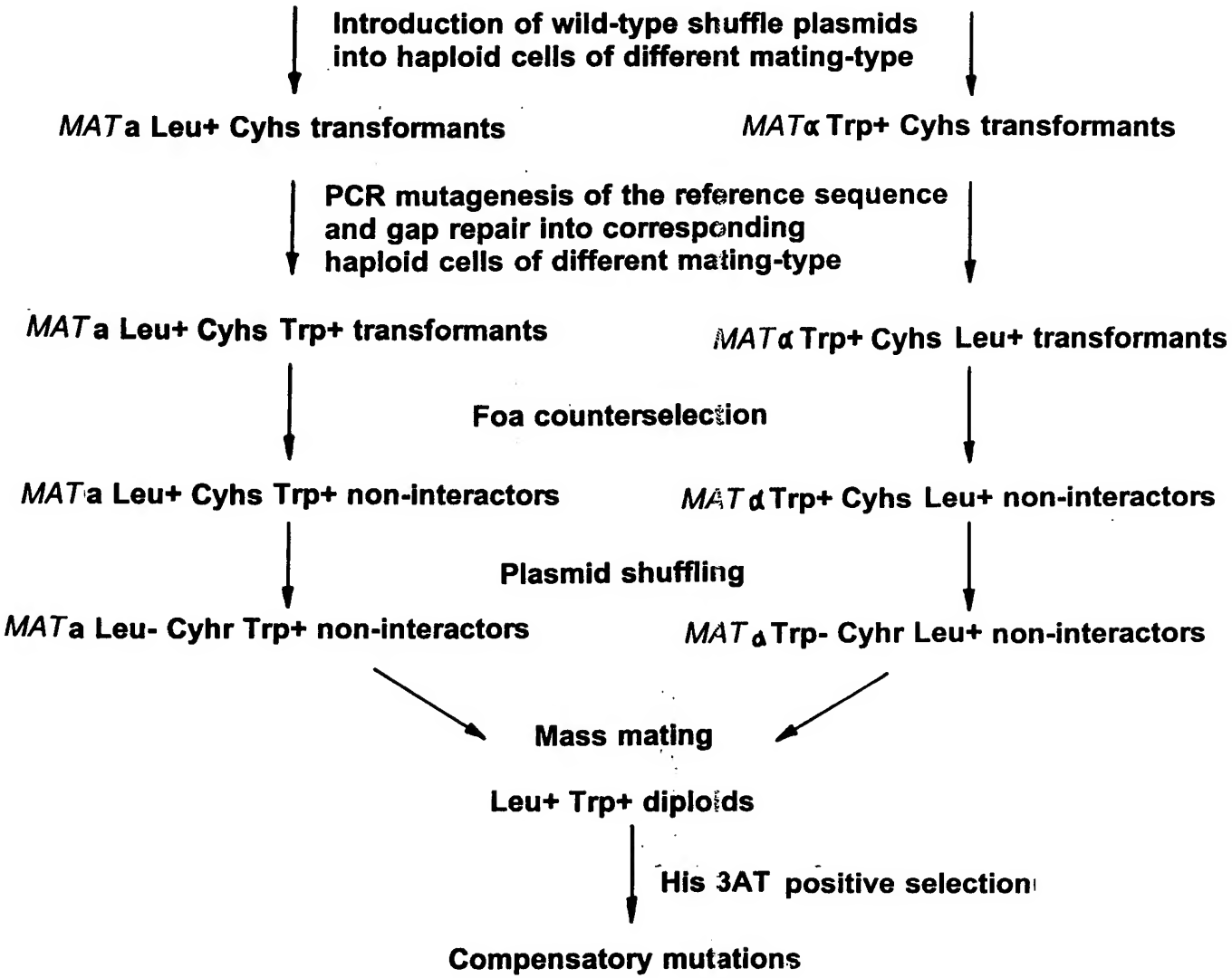

FIG. 23A

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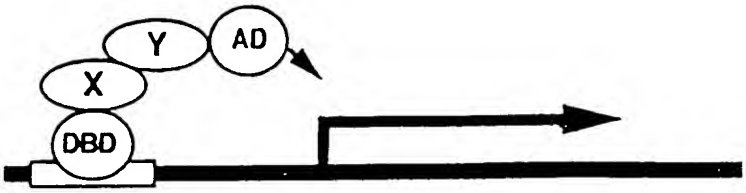
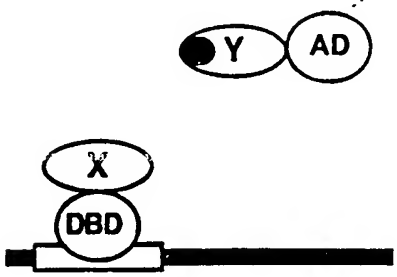


Sensitivity

Mutagenesis of X (or Y) partner

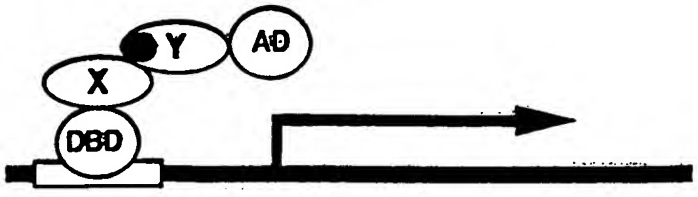
SELECTION for Foa Resistance



(Restrictive conditions)

Replica-plating

SELECTION for Ura/His growth



(Permissive conditions)

FIG. 23B

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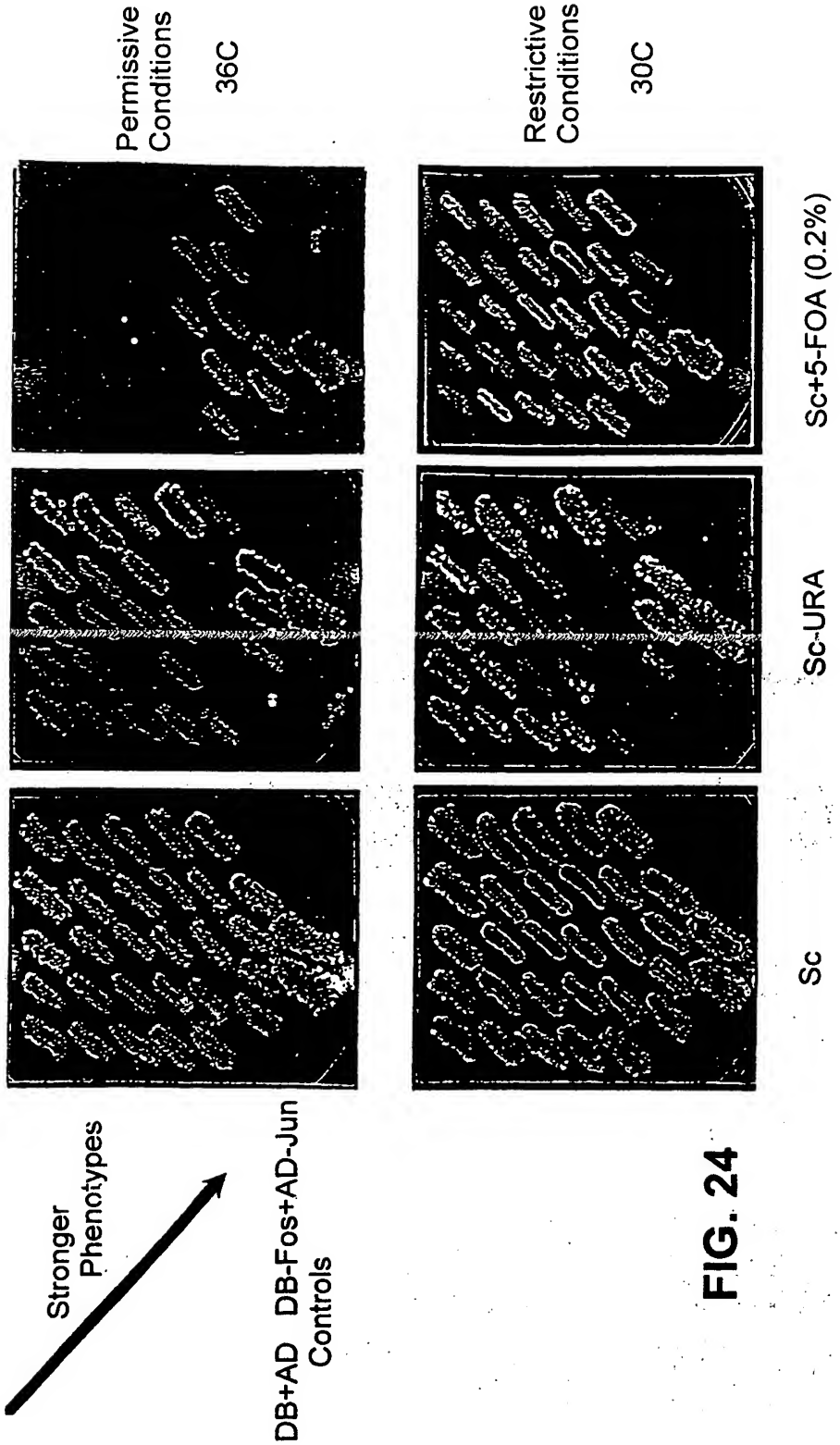

FIG. 24

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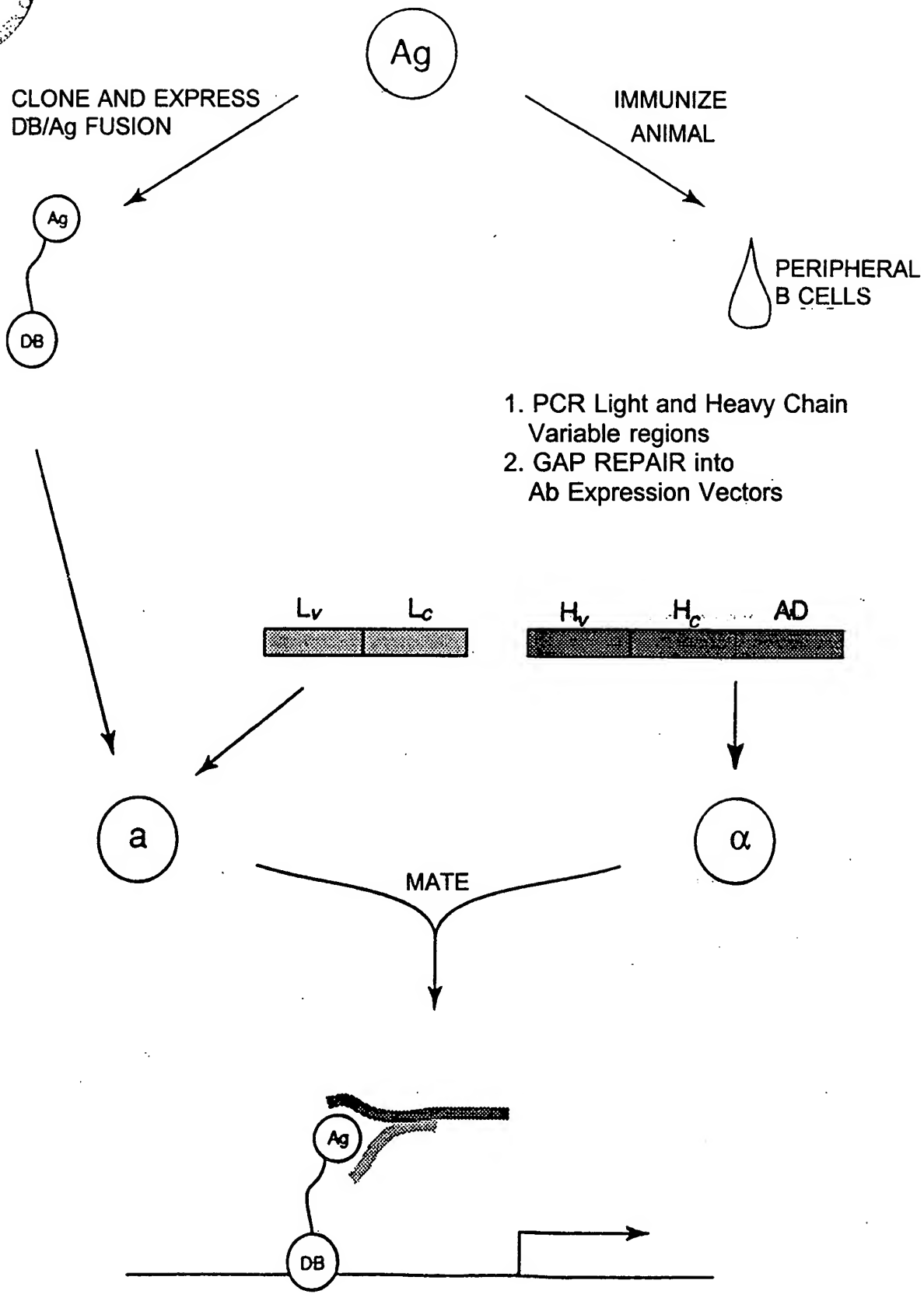

FIG. 25